

ABSTRACT OF THE DISCLOSURE

An analyzing apparatus comprising an small-angle X-ray scattering device, a mass spectrometer, a sample holder, a sample temperature control device, and a control device. The scattering device applies an X-ray to a sample and detects an X-ray generated from the sample. The mass spectrometer analyzes the gas generated from the sample. The sample holder holds the sample at a position common to the scattering device and the mass spectrometer. The sample temperature control device controls the temperature of the sample. The control device controls the scattering device and the mass spectrometer, making them to perform measuring processes at the same time. The scattering device and the mass spectrometer can measure the sample in the same condition because the sample remains at the same position while they are operating. Therefore, the scattering device and the mass spectrometer acquire data items at the same time about the same sample that remains in the same condition. Hence, the analyzing apparatus can correctly determine the cause of change in characteristics of the sample, if the characteristics of the sample change due to, for example, a temperature change.